

# The Most Complete Jitter and Serial Data Solution

The following table compares the feature set of TDSJIT3, Jitter and Timing analysis, and TDSRT-Eye™, Serial Data Compliance and Analysis. Both packages include data jitter measurement and analysis including Total Jitter @ 10<sup>-12</sup> BER. TDSJIT3 provides a wide range of jitter and timing analysis for high-speed digital design (serial and parallel), while TDSRT-Eye provides the compliance results to emerging serial data standards. Take advantage of the power of both software packages at a reduced price by ordering the TDSJIT3/RT-Eye software bundle (Opt. RTJ) with either the TDS6000 Series or TDS/CSA7000 Series (1.5GHz models and above). Existing TDSJIT3 customers can also upgrade to Opt. RTJ at a very attractive discount price until December 31<sup>st</sup>, 2003. Consult your Tektronix Sales Representative for details.

Feature Comparison	Software Bundle Opt RTJ Includes both TDSJIT3 and RT-Eye	
	TDSJIT3 (Opt JT3)	TDS RT-Eye (Opt RTE)
Primary Application	Advance Jitter Analysis	Serial Compliance & Analysis
<b>Serial Data Timing Measurements</b>		
▶ Waveform Eye Width	No	<b>Yes</b>
▶ Rise Time	Yes	Yes
▶ Fall Time	Yes	Yes
▶ Unit Interval	Data Period	<b>Yes</b>
▶ Bit Rate	Data Frequency	<b>Yes</b>
▶ Differential Skew	No	<b>Yes</b>
▶ Units in Seconds or UI	No	<b>Yes</b>
<b>Serial Data Amplitude Measurements</b>		
▶ Eye Height	No	<b>Yes</b>
▶ Differential Voltage (cycle-cycle)	No	<b>Yes</b>
▶ High Amplitude	No	<b>Yes</b>
▶ Low Amplitude	No	<b>Yes</b>
▶ Common Mode DC	No	<b>Yes</b>
▶ Common Mode AD	No	<b>Yes</b>
▶ De-Emphasis	No	<b>Yes</b>
<b>Serial Data Jitter Measurements</b>		
▶ Data TIE	Yes	Yes
▶ Jitter @BERT (RJ,D,PJ,DDJ,DCD)	Yes	Yes
▶ Jitter Eye Opening	Yes	Yes
<b>Standard Clock Recovery Techniques</b>		
Constant: Mean	Yes	Yes
Constant: Median	No	<b>Yes</b>
Smart Gating	No	<b>Yes</b>
Golden PLL	Yes	Yes

Feature Comparison	Software Bundle Opt RTJ Includes both TDSJIT3 and RT-Eye	
	TDSJIT3 (Opt JT3)	TDS RT-Eye (Opt RTE)
Primary Application	Advance Jitter Analysis	Serial Compliance & Analysis
▶ Custom PLL	Yes	Yes
<b>Clock Jitter Measurements</b>		
▶ Adjacent cycle	Yes	No
▶ Period	Yes	No
▶ Frequency	Yes	No
▶ Cycle-cycle	Yes	No
▶ N-cycle	Yes	No
▶ Skew	Yes	No
▶ Duty cycle	Yes	No
▶ Duty cycle error	Yes	Use DCD on Clock
▶ Differential Crossover Voltage	Yes	No
▶ TIE	Yes	Use Data TIE on Clock
▶ Rambus DRCG	Yes	No
<b>General</b>		
▶ Pulse width	Yes	No
▶ High time	Yes	No
▶ Low time	Yes	No
<b>Clock to Data</b>		
▶ Setup	Yes	No
▶ Hold	Yes	No
<b>Data</b>		
▶ Data frequency	Yes	Yes
▶ Data period	Yes	Yes
▶ Data TIE	Yes	Yes
<b>Plots/Analysis</b>		
▶ Real Time Eye (RT-Eye) Rendering	No	Yes
▶ Jitter spectrum	Yes	Yes
▶ Modulation analysis	Yes	Yes
▶ Jitter profile	Yes	Yes
▶ Profile filter	Yes	Yes
▶ Worst offender analysis	Yes	Yes
▶ DJ-RJ	Yes	Yes
▶ Data Patterns	Yes	Yes
▶ Histogram	Yes	Yes
▶ BER estimation (bathtub curves)	Yes	Yes
▶ Histogram Bin Analysis	Yes	Yes
▶ Analysis Data Export .CVB	Yes	Yes
<b>Plots/Analysis</b>		
▶ Qualify input	Yes	Yes
▶ Population control	Yes	Yes
▶ Per-acquisition statistics	Yes	Yes
▶ Large Displacement	Yes	Yes
▶ Jitter AutoSet	Yes	Yes
▶ GPIB controlled	Yes	Yes
<b>Standards Compliance Testing</b>		
▶ Infiniband	No	Yes (with Opt. IBA)
▶ PCI Express	No	Yes (with Opt. PCE)
▶ User (Custom Masks and Limits)	No	Yes
<b>Real Time Eye Mask Testing</b>	No	Yes

Feature Comparison	Software Bundle Opt RTJ Includes both TDSJIT3 and RT-Eye	
	TDSJIT3 (Opt JT3)	TDS RT-Eye (Opt RTE)
Primary Application	Advance Jitter Analysis	Serial Compliance & Analysis
▶ Test Pattern Recognition	No	<b>Yes</b>
Deemphasis Bit Selection	No	<b>Yes</b>
Mask Hit Measurements	No	<b>Yes</b>
<b>Full Report Generation</b>		
▶ Customizable Report Tool	No	<b>Yes</b>

Legend: 

<b>Yes</b>
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 Means unique to package